

<b>Notice of References Cited</b>	Application/Control No. 10/528,400		Applicant(s)/Patent Under Reexamination SIEKE ET AL.	
	Examiner Edward F. Landrum		Art Unit 3724	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,848,471	12-1998	Freeland, Jay	30/280
*	B	US-4,693,004	09-1987	Plana, Salvio	30/265
*	C	US-5,044,081	09-1991	Nguyen, Tan D.	30/294
*	D	US-4,604,802	08-1986	Samuelsson, Soren	30/124
*	E	US-2001/0034919	11-2001	Faggiotto, Elberino	15/236.06
*	F	US-5,809,652	09-1998	Ducret, Lucien C.	30/90.7
*	G	US-5,381,601	01-1995	Danter et al.	30/90.1
*	H	US-2,013,893	09-1935	Matthews, Ross R.	83/455
*	I	US-6,581,291	06-2003	Tarpill et al.	30/90.4
*	J	US-3,611,571	10-1971	Belling, William F.	30/280
*	K	US-3,886,657	06-1975	Fabian, Ralf	30/294
*	L	US-5,285,577	02-1994	Carney et al.	30/294
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE29606561U1	04-1998	Germany	Wessels, Helmut	B26D 3/28
	O	DE4110799A1	04-1991	Germany	Diebold, Manfred	B60S 5/00
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.